

Notice of References Cited	Application/Control No. 10/063,980	Applicant(s)/Patent Under Reexamination DEWANJEE, PIJUSH K.	
	Examiner David Buttner	Art Unit 1712	Page 1 of 1

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	B	US-6,486,261	11-2002	Wu et al.	525/332.6
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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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	U	chemical registry # 5285-60-9
	V	chemical registry #13680-35-8
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